



**PATENT**  
29250-000750/US

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Robert E. MYER Conf. No. 2373  
Application No.: 09/656,933 Group No. 2829  
Filing Date: September 7, 2000 Examiner: Jimmy Nguyen  
Title: IMPROVED RF TEST PROBE

**AMENDMENT UNDER 37 C.F.R. §1.116**

Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

December 23, 2003

Sir:

Responsive to the final Office Action mailed July 24, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

**Listing of the claims and their current status** begins on page 2 of this paper.

**Remarks** begin on page 6 of this paper.